

Search Notes



Application/Control No.

10/608,771

Examiner

Duc M. Nguyen

Applicant(s)/Patent under
Reexamination

EIDEN, NIKO

Art Unit

2685 *2618*

SEARCHED

Class	Subclass	Date	Examiner
455	567		
	414.1		
	414.2		
	415		
	401		
340	7.52		
	7.6	<i>10/27/05</i>	<i>DN</i>
<i>Updated</i>		<i>4/11/06</i>	<i>DN</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	10/22/2005	DN
EAST	10/27/2005	DN